

L Number	Hits	Search Text	DB	Time stamp
-	1974	438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.	USPAT	2004/04/09 13:53
-	1794	324/765.cccls.	USPAT	2004/04/08 18:36
-	1829	(438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) not 324/765.cccls.	USPAT	2004/04/06 20:44
-	788	((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) not 324/765.cccls.) and voltage	USPAT	2004/03/25 15:28
-	2000	438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.	USPAT	2004/03/29 14:30
-	27	(438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) and (probe adj tip)	USPAT	2004/03/25 14:52
-	15	(semiconductor and (electric adj field) and voltage and detect\$3) and (stimulate with circuit\$2)	USPAT	2004/03/25 15:32
-	577	DUT with voltage	USPAT	2004/03/29 14:30
-	2000	438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.	USPAT	2004/03/29 14:30
-	459	(DUT with voltage) not ((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.)	USPAT	2004/03/29 14:31
-	1831	324/765.cccls.	USPAT	2004/04/06 20:16
-	262	324/765.cccls. and DUT	USPAT	2004/04/06 20:16
-	3	(("6417680") or ("6412086") or ("5493236")).PN.	USPAT	2004/04/06 20:44
-	737	scanning adj probe adj microscope	USPAT	2004/04/08 18:37
-	2022	438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.	USPAT	2004/04/08 18:36
-	1831	324/765.cccls.	USPAT	2004/04/08 18:37
-	3703	(438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.	USPAT	2004/04/08 18:37
-	14	((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.) and (scanning adj probe adj microscope)	USPAT	2004/04/08 18:44
-	42	((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.) and (atomic adj force adj microscope)	USPAT	2004/04/08 18:45
-	29	((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.) and (atomic adj force adj microscope)) not (((438/5.cccls. or 438/10.cccls. or 438/11.cccls. or 438/12.cccls. or 438/14.cccls. or 438/17.cccls. or 438/18.cccls.) or 324/765.cccls.) and (scanning adj probe adj microscope))	USPAT	2004/04/08 18:45
-	82	AFM with nanometer	USPAT	2004/04/09 14:07
-	14	AFM and ((probe adj tip) with nanometer)	USPAT	2004/04/09 14:14

-		1	"6448096"	USPAT	2004/04/09 14:58
-		0	"6448096" and nanometer	USPAT	2004/04/09 14:15
-		0	"6448096" and nanometers	USPAT	2004/04/09 14:15
-		0	"6448096" and nano\$6	USPAT	2004/04/09 14:15
-		1	"6448096" and flip	USPAT	2004/04/09 14:59